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Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I ² C, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	12
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 150°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	16-TSSOP
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Chapter 3 Modes of Operation



Chapter 4 Memory

Table 4-2. Direct-Page Register Summary (Sheet 1 of 3)

Address	Register Name	Bit 7	6	5	4	3	2	1	Bit 0
0x00 00	PTAD	PTAD7	PTAD6	_	—	PTAD3	PTAD2	PTAD1	PTAD0
0x00 01	PTADD	PTADD7	PTADD6	_		PTADD3	PTADD2	PTADD1	PTADD0
0x00 02	PTBD	PTBD7	PTBD6	PTBD5	PTBD4	PTBD3	PTBD2	PTBD1	PTBD0
0x00 03	PTBDD	PTBDD7	PTBDD6	PTBDD5	PTBDD4	PTBDD3	PTBDD2	PTBDD1	PTBDD0
0x00 04	PTCD	PTCD7	PTCD6	PTCD5	PTCD4	PTCD3	PTCD2	PTCD1	PTCD0
0x00 05	PTCDD	PTCDD7	PTCDD6	PTCDD5	PTCDD4	PTCDD3	PTCDD2	PTCDD1	PTCDD0
0x00 06	Reserved	_			_				_
0x00 07	Reserved		—		_	_	0	0	0
0x00 08 –0 x00 0D	Reserved		_						_
0x00 0E	ACMPSC	ACME	ACBGS	ACF	ACIE	ACO	ACOPE	ACMOD1	ACMOD0
0x00 0F	Reserved		—		_				—
0x00 10	ADCSC1	COCO	AIEN	ADCO			ADCH		
0x00 11	ADCSC2	ADACT	ADTRG	ACFE	ACFGT				_
0x00 12	ADCRH	0	0	0	0	0	0	ADR9	ADR8
0x00 13	ADCRL	ADR7	ADR6	ADR5	ADR4	ADR3	ADR2	ADR1	ADR0
0x00 14	ADCVH	0	0	0	0	0	0	ADCV9	ADCV8
0x00 15	ADCVL	ADCV7	ADCV6	ADCV5	ADCV4	ADCV3	ADCV2	ADCV1	ADCV0
0x00 16	ADCCFG	ADLPC	AD	NΛ	ADLSMP	MODE		ADICLK	
0x00 17	APCTL1	ADPC7	ADPC6	ADPC5	ADPC4	ADPC3	ADPC2	ADPC1	ADPC0
0x00 18	APCTL2	ADPC15	ADPC14	ADPC13	ADPC12	ADPC11	ADPC10	ADPC9	ADPC8
0x00 19 –0 x00 1B	Reserved	_	_	_	_	_	_	_	_
0x00 1C	MTIMSC	TOF	TOIE	TRST	TSTP	0	0	0	0
0x00 1D	MTIMCLK	0	0	CL	KS		Р	S	
0x00 1E	MTIMCNT				CI	NT			
0x00 1F	MTIMMOD				МС	DD			
0x00 20	TPM1SC	TOF	TOIE	CPWMS	CLKSB	CLKSA	PS2	PS1	PS0
0x00 21	TPM1CNTH	Bit 15	14	13	12	11	10	9	Bit 8
0x00 22	TPM1CNTL	Bit 7	6	5	4	3	2	1	Bit 0
0x00 23	TPM1MODH	Bit 15	14	13	12	11	10	9	Bit 8
0x00 24	TPM1MODL	Bit 7	6	5	4	3	2	1	Bit 0
0x00 25	TPM1C0SC	CH0F	CH0IE	MS0B	MS0A	ELS0B	ELS0A	0	0
0x00 26	TPM1C0VH	Bit 15	14	13	12	11	10	9	Bit 8
0x00 27	TPM1C0VL	Bit 7	6	5	4	3	2	1	Bit 0
0x00 28	TPM1C1SC	CH1F	CH1IE	MS1B	MS1A	ELS1B	ELS1A	0	0
0x00 29	TPM1C1VH	Bit 15	14	13	12	11	10	9	Bit 8
0x00 2A	TPM1C1VL	Bit 7	6	5	4	3	2	1	Bit 0

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4.4 RAM

The MC9S08SG32 Series includes static RAM. The locations in RAM below 0x0100 can be accessed using the more efficient direct addressing mode, and any single bit in this area can be accessed with the bit manipulation instructions (BCLR, BSET, BRCLR, and BRSET). Locating the most frequently accessed program variables in this area of RAM is preferred.

The RAM retains data when the MCU is in low-power wait, stop2, or stop3 mode. At power-on the contents of RAM are uninitialized. RAM data is unaffected by any reset provided that the supply voltage does not drop below the minimum value for RAM retention (V_{RAM}).

For compatibility with M68HC05 MCUs, the HCS08 resets the stack pointer to 0x00FF. In the MC9S08SG32 Series, it is usually best to reinitialize the stack pointer to the top of the RAM so the direct page RAM can be used for frequently accessed RAM variables and bit-addressable program variables. Include the following 2-instruction sequence in your reset initialization routine (where RamLast is equated to the highest address of the RAM in the Freescale Semiconductor-provided equate file).

LDHX #RamLast+1 ;point one past RAM TXS ;SP<-(H:X-1)

When security is enabled, the RAM is considered a secure memory resource and is not accessible through BDM or through code executing from non-secure memory. See Section 4.6, "Security", for a detailed description of the security feature.

4.5 FLASH

The FLASH memory is intended primarily for program storage. In-circuit programming allows the operating program to be loaded into the FLASH memory after final assembly of the application product. It is possible to program the entire array through the single-wire background debug interface. Because no special voltages are needed for FLASH erase and programming operations, in-application programming is also possible through other software-controlled communication paths. For a more detailed discussion of in-circuit and in-application programming, refer to the *HCS08 Family Reference Manual, Volume I,* Freescale Semiconductor document order number HCS08RMv1/D.



Chapter 4 Memory

The first byte of a series of sequential bytes being programmed in burst mode will take the same amount of time to program as a byte programmed in standard mode. Subsequent bytes will program in the burst program time provided that the conditions above are met. In the case the next sequential address is the beginning of a new row, the program time for that byte will be the standard time instead of the burst time. This is because the high voltage to the array must be disabled and then enabled again. If a new burst command has not been queued before the current command completes, then the charge pump will be disabled and high voltage removed from the array.



MC9S08SG32 Data Sheet, Rev. 8



Table 5-3. SRS Register Field Descriptions

Field	Description
3 ILAD	Illegal Address — Reset was caused by an attempt to access either data or an instruction at an unimplemented memory address. 0 Reset not caused by an illegal address 1 Reset caused by an illegal address
1 LVD	 Low Voltage Detect — If the LVDRE bit is set and the supply drops below the LVD trip voltage, an LVD reset will occur. This bit is also set by POR. 0 Reset not caused by LVD trip or POR. 1 Reset caused by LVD trip or POR.

5.7.2 System Background Debug Force Reset Register (SBDFR)

This high page register contains a single write-only control bit. A serial background command such as WRITE_BYTE must be used to write to SBDFR. Attempts to write this register from a user program are ignored. Reads always return 0x00.



¹ BDFR is writable only through serial background debug commands, not from user programs.

Figure 5-3. System Background Debug Force Reset Register (SBDFR)

Table 5-4. SBDFR Register Field Descriptions

Field	Description
0 BDFR	Background Debug Force Reset — A serial background command such as WRITE_BYTE can be used to allow an external debug host to force a target system reset. Writing 1 to this bit forces an MCU reset. This bit cannot be written from a user program.



Chapter 6 Parallel Input/Output Control

6.6.1.7 Port A Interrupt Pin Select Register (PTAPS)



Figure 6-9. Port A Interrupt Pin Select Register (PTAPS)

Table 6-8. PTAPS Register Field Descriptions

Field	Description
3:0 PTAPS[3:0]	 Port A Interrupt Pin Selects — Each of the PTAPSn bits enable the corresponding port A interrupt pin. 0 Pin not enabled as interrupt. 1 Pin enabled as interrupt.

6.6.1.8 Port A Interrupt Edge Select Register (PTAES)

	7	6	5	4	3	2	1	0
R	0	0	0	0	DTAES2			DTAESO
W					FIAE33	F IAE32	FIAEST	FIALOU
Reset:	0	0	0	0	0	0	0	0

Figure 6-10. Port A Edge Select Register (PTAES)

Table 6-9. PTAES Register Field Descriptions

Field	Description
3:0 PTAES[3:0]	 Port A Edge Selects — Each of the PTAESn bits serves a dual purpose by selecting the polarity of the active interrupt edge as well as selecting a pull-up or pull-down device if enabled. 0 A pull-up device is connected to the associated pin and detects falling edge/low level for interrupt generation. 1 A pull-down device is connected to the associated pin and detects rising edge/high level for interrupt generation.



Chapter 6 Parallel Input/Output Control

6.6.3.3 Port C Pull Enable Register (PTCPE)



Figure 6-21. Internal Pull Enable for Port C Register (PTCPE)

Table 6-20. PTCPE Register Field Descriptions

Field	Description
7:0 PTCPE[7:0]	 Internal Pull Enable for Port C Bits — Each of these control bits determines if the internal pull-up device is enabled for the associated PTC pin. For port C pins that are configured as outputs, these bits have no effect and the internal pull devices are disabled. 0 Internal pull-up device disabled for port C bit n. 1 Internal pull-up device enabled for port C bit n.

6.6.3.4 Port C Slew Rate Enable Register (PTCSE)

_	7	6	5	4	3	2	1	0
R W	PTCSE7	PTCSE6	PTCSE5	PTCSE4	PTCSE3	PTCSE2	PTCSE1	PTCSE0
Reset:	0	0	0	0	0	0	0	0

Figure 6-22. Slew Rate Enable for Port C Register (PTCSE)

Table 6-21. PTCSE Register Field Descriptions

Field	Description
7:0 PTCSE[7:0]	 Output Slew Rate Enable for Port C Bits — Each of these control bits determines if the output slew rate control is enabled for the associated PTC pin. For port C pins that are configured as inputs, these bits have no effect. 0 Output slew rate control disabled for port C bit n. 1 Output slew rate control enabled for port C bit n.



Sourco		e		es	Cup by Cup	Affecton CCR		
Form	Operation	Addre Mod	Object Code	Cycle	Details	V 1 1 H	INZC	
BCC rel	Branch if Carry Bit Clear (if C = 0)	REL	24 rr	3	qqq	- 1 1 -		
BCLR n,opr8a	Clear Bit n in Memory (Mn ← 0)	DIR (b0) DIR (b1) DIR (b2) DIR (b3) DIR (b4) DIR (b5) DIR (b6) DIR (b7)	11 dd 13 dd 15 dd 17 dd 19 dd 1B dd 1D dd 1F dd	5 5 5 5 5 5 5 5 5	rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp rfwpp	- 1 1 -		
BCS rel	Branch if Carry Bit Set (if C = 1)(Same as BLO)	REL	25 rr	3	qqq	- 1 1 -		
BEQ rel	Branch if Equal (if Z = 1)	REL	27 rr	3	ppp	- 1 1 -		
BGE rel	Branch if Greater Than or Equal To (if $N \oplus V = 0$) (Signed)	REL	90 rr	3	qqq	- 1 1 -		
BGND	Enter active background if ENBDM=1 Waits for and processes BDM commands until GO, TRACE1, or TAGGO	INH	82	5+	fpppp	- 1 1 -		
BGT rel	Branch if Greater Than (if $Z (N \oplus V) = 0$) (Signed)	REL	92 rr	3	qqq	- 1 1 -		
BHCC rel	Branch if Half Carry Bit Clear (if H = 0)	REL	28 rr	3	qqq	- 1 1 -		
BHCS rel	Branch if Half Carry Bit Set (if H = 1)	REL	29 rr	3	qqq	- 1 1 -		
BHI rel	Branch if Higher (if C Z = 0)	REL	22 rr	3	qqq	- 1 1 -		
BHS rel	Branch if Higher or Same (if $C = 0$) (Same as BCC)	REL	24 rr	3	qqq	- 1 1 -		
BIH rel	Branch if IRQ Pin High (if IRQ pin = 1)	REL	2F rr	3	ppp	- 1 1 -		
BIL rel	Branch if IRQ Pin Low (if IRQ pin = 0)	REL	2E rr	3	qqq	- 1 1 -		
BIT #opr8i BIT opr8a BIT opr16a BIT oprx16,X BIT oprx8,X BIT ,X BIT oprx16,SP BIT oprx8,SP	Bit Test (A) & (M)(CCR Updated but Operands Not Changed)	IMM DIR EXT IX2 IX1 IX SP2 SP1	A5 ii B5 dd C5 hh ll D5 ee ff E5 ff F5 9E D5 ee ff 9E E5 ff	2 3 4 3 3 5 4	pp rpp prpp rpp rfp pprpp prpp	011-	- ‡ ‡ -	
BLE rel	Branch if Less Than or Equal To (if Z (N \oplus V) = 1) (Signed)	REL	93 rr	3	qqq	- 1 1 -		
BLO rel	Branch if Lower (if $C = 1$) (Same as BCS)	REL	25 rr	3	qqq	- 1 1 -		
BLS rel	Branch if Lower or Same (if C Z = 1)	REL	23 rr	3	qqq	- 1 1 -		
BLT rel	Branch if Less Than (if $N \oplus V = 1$) (Signed)	REL	91 rr	3	qqq	- 1 1 -		
BMC rel	Branch if Interrupt Mask Clear (if I = 0)	REL	2C rr	3	qqq	- 1 1 -		
BMI rel	Branch if Minus (if N = 1)	REL	2B rr	3	qqq	- 1 1 -		
BMS rel	Branch if Interrupt Mask Set (if I = 1)	REL	2D rr	3	qqq	- 1 1 -		
BNE rel	Branch if Not Equal (if Z = 0)	REL	26 rr	3	ppp	- 1 1 -		

Table 7-2. Instruction Set Summary (Sheet 2 of 9)

Chapter 9 Analog-to-Digital Converter (S08ADC10V1)

ADCH	Channel	Input	ADCH	Channel
01111	AD15	PTC7/ADP15	11111	Module Disabled

Table 9-1. ADC Channel Assignment (continued)

¹ For information, see Section 9.1.5, "Temperature Sensor".

² Requires BGBE =1 in SPMSC1 see Section 5.7.6, "System Power Management Status and Control 1 Register (SPMSC1)". For value of bandgap voltage reference see A.6, "DC Characteristics".

9.1.2 Analog Power and Ground Signal Names

References to V_{DDAD} and V_{SSAD} in this chapter correspond to signals V_{DDA} and V_{SSA} , respectively.

9.1.3 Alternate Clock

The ADC module is capable of performing conversions using the MCU bus clock, the bus clock divided by two, the local asynchronous clock (ADACK) within the module, or the alternate clock, ALTCLK. The alternate clock for the MC9S08SG32 Series MCU devices is the external reference clock (ICSERCLK).

The selected clock source must run at a frequency such that the ADC conversion clock (ADCK) runs at a frequency within its specified range (f_{ADCK}) after being divided down from the ALTCLK input as determined by the ADIV bits.

ALTCLK is active while the MCU is in wait mode provided the conditions described above are met. This allows ALTCLK to be used as the conversion clock source for the ADC while the MCU is in wait mode.

ALTCLK cannot be used as the ADC conversion clock source while the MCU is in either stop2 or stop3.

9.1.4 Hardware Trigger

The ADC hardware trigger, ADHWT, is the output from the real time counter (RTC). The RTC counter can be clocked by either ICSERCLK, ICSIRCLK or a nominal 1 kHz clock source.

The period of the RTC is determined by the input clock frequency, the RTCPS bits, and the RTCMOD register. When the ADC hardware trigger is enabled, a conversion is initiated upon an RTC counter overflow. The RTIE does not have to be set for RTC to cause a hardware trigger.

The RTC can be configured to cause a hardware trigger in MCU run, wait, and stop3.

9.1.5 Temperature Sensor

To use the on-chip temperature sensor, the user must perform the following:

- Configure ADC for long sample with a maximum of 1 MHz clock
- Convert the bandgap voltage reference channel (AD27)
 - By converting the digital value of the bandgap voltage reference channel using the value of V_{BG} the user can determine V_{DD}. For value of bandgap voltage, see Section A.6, "DC Characteristics".
- Convert the temperature sensor channel (AD26)

Input None



Chapter 9 Analog-to-Digital Converter (S08ADC10V1)

9.4.4.2 Completing Conversions

A conversion is completed when the result of the conversion is transferred into the data result registers, ADCRH and ADCRL. This is indicated by the setting of COCO. An interrupt is generated if AIEN is high at the time that COCO is set.

A blocking mechanism prevents a new result from overwriting previous data in ADCRH and ADCRL if the previous data is in the process of being read while in 10-bit MODE (the ADCRH register has been read but the ADCRL register has not). When blocking is active, the data transfer is blocked, COCO is not set, and the new result is lost. In the case of single conversions with the compare function enabled and the compare condition false, blocking has no effect and ADC operation is terminated. In all other cases of operation, when a data transfer is blocked, another conversion is initiated regardless of the state of ADCO (single or continuous conversions enabled).

If single conversions are enabled, the blocking mechanism could result in several discarded conversions and excess power consumption. To avoid this issue, the data registers must not be read after initiating a single conversion until the conversion completes.

9.4.4.3 Aborting Conversions

Any conversion in progress is aborted when:

- A write to ADCSC1 occurs (the current conversion will be aborted and a new conversion will be initiated, if ADCH are not all 1s).
- A write to ADCSC2, ADCCFG, ADCCVH, or ADCCVL occurs. This indicates a mode of operation change has occurred and the current conversion is therefore invalid.
- The MCU is reset.
- The MCU enters stop mode with ADACK not enabled.

When a conversion is aborted, the contents of the data registers, ADCRH and ADCRL, are not altered. However, they continue to be the values transferred after the completion of the last successful conversion. If the conversion was aborted by a reset, ADCRH and ADCRL return to their reset states.

9.4.4.4 Power Control

The ADC module remains in its idle state until a conversion is initiated. If ADACK is selected as the conversion clock source, the ADACK clock generator is also enabled.

Power consumption when active can be reduced by setting ADLPC. This results in a lower maximum value for f_{ADCK} (see the electrical specifications).

9.4.4.5 Sample Time and Total Conversion Time

The total conversion time depends on the sample time (as determined by ADLSMP), the MCU bus frequency, the conversion mode (8-bit or 10-bit), and the frequency of the conversion clock (f_{ADCK}). After the module becomes active, sampling of the input begins. ADLSMP selects between short and long sample times. When sampling is complete, the converter is isolated from the input channel and a successive



- Average the result by converting the analog input many times in succession and dividing the sum of the results. Four samples are required to eliminate the effect of a 1LSB, one-time error.
- Reduce the effect of synchronous noise by operating off the asynchronous clock (ADACK) and averaging. Noise that is synchronous to ADCK cannot be averaged out.

9.6.2.4 Code Width and Quantization Error

The ADC quantizes the ideal straight-line transfer function into 1024 steps (in 10-bit mode). Each step ideally has the same height (1 code) and width. The width is defined as the delta between the transition points to one code and the next. The ideal code width for an N bit converter (in this case N can be 8 or 10), defined as 1LSB, is:

$1LSB = (V_{REFH} - V_{REFL}) / 2^{N}$ Eqn. 9-2

There is an inherent quantization error due to the digitization of the result. For 8-bit or 10-bit conversions the code transitions when the voltage is at the midpoint between the points where the straight line transfer function is exactly represented by the actual transfer function. Therefore, the quantization error will be \pm 1/2LSB in 8- or 10-bit mode. As a consequence, however, the code width of the first (0x000) conversion is only 1/2LSB and the code width of the last (0xFF or 0x3FF) is 1.5LSB.

9.6.2.5 Linearity Errors

The ADC may also exhibit non-linearity of several forms. Every effort has been made to reduce these errors but the system should be aware of them because they affect overall accuracy. These errors are:

- Zero-scale error (E_{ZS}) (sometimes called offset) This error is defined as the difference between the actual code width of the first conversion and the ideal code width (1/2LSB). If the first conversion is 0x001, then the difference between the actual 0x001 code width and its ideal (1LSB) is used.
- Full-scale error (E_{FS}) This error is defined as the difference between the actual code width of the last conversion and the ideal code width (1.5LSB). If the last conversion is 0x3FE, then the difference between the actual 0x3FE code width and its ideal (1LSB) is used.
- Differential non-linearity (DNL) This error is defined as the worst-case difference between the actual code width and the ideal code width for all conversions.
- Integral non-linearity (INL) This error is defined as the highest-value the (absolute value of the) running sum of DNL achieves. More simply, this is the worst-case difference of the actual transition voltage to a given code and its corresponding ideal transition voltage, for all codes.
- Total unadjusted error (TUE) This error is defined as the difference between the actual transfer function and the ideal straight-line transfer function and includes all forms of error.

9.6.2.6 Code Jitter, Non-Monotonicity, and Missing Codes

Analog-to-digital converters are susceptible to three special forms of error. These are code jitter, non-monotonicity, and missing codes.

Code jitter is when, at certain points, a given input voltage converts to one of two values when sampled repeatedly. Ideally, when the input voltage is infinitesimally smaller than the transition voltage, the



Chapter 12 Modulo Timer (S08MTIMV1)

12.3.3 MTIM Counter Register (MTIMCNT)

MTIMCNT is the read-only value of the current MTIM count of the 8-bit counter.



Figure 12-6. MTIM Counter Register



Field	Description
7:0 COUNT	MTIM Count — These eight read-only bits contain the current value of the 8-bit counter. Writes have no effect to this register. Reset clears the count to \$00.

12.3.4 MTIM Modulo Register (MTIMMOD)



Figure 12-7. MTIM Modulo Register

Table 12-5. MTIM Modulo F	Register Field Descriptions
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Field	Description
7:0 MOD	MTIM Modulo — These eight read/write bits contain the modulo value used to reset the count and set TOF. A value of \$00 puts the MTIM in free-running mode. Writing to MTIMMOD resets the COUNT to \$00 and clears TOF. Reset sets the modulo to \$00.





Figure 14-5. SCI Baud Rate Register (SCIBDL)

Table 14-2. SCIBDL Field Descriptions

Field	Description
7:0 SBR[7:0]	Baud Rate Modulo Divisor — These 13 bits in SBR[12:0] are referred to collectively as BR, and they set the modulo divide rate for the SCI baud rate generator. When BR = 0, the SCI baud rate generator is disabled to reduce supply current. When BR = 1 to 8191, the SCI baud rate = BUSCLK/(16×BR). See also BR bits in Table 14-1.

14.2.2 SCI Control Register 1 (SCIC1)

This read/write register is used to control various optional features of the SCI system.

	7	6	5	4	3	2	1	0
R W	LOOPS	SCISWAI	RSRC	М	WAKE	ILT	PE	PT
Reset	0	0	0	0	0	0	0	0

Figure 14-6. SCI Control Register 1 (SCIC1)

Table 14-3. SCIC1 Field Descriptions

Field	Description
7 LOOPS	 Loop Mode Select — Selects between loop back modes and normal 2-pin full-duplex modes. When LOOPS = 1, the transmitter output is internally connected to the receiver input. 0 Normal operation — RxD and TxD use separate pins. 1 Loop mode or single-wire mode where transmitter outputs are internally connected to receiver input. (See RSRC bit.) RxD pin is not used by SCI.
6 SCISWAI	 SCI Stops in Wait Mode 0 SCI clocks continue to run in wait mode so the SCI can be the source of an interrupt that wakes up the CPU. 1 SCI clocks freeze while CPU is in wait mode.
5 RSRC	 Receiver Source Select — This bit has no meaning or effect unless the LOOPS bit is set to 1. When LOOPS = 1, the receiver input is internally connected to the TxD pin and RSRC determines whether this connection is also connected to the transmitter output. Provided LOOPS = 1, RSRC = 0 selects internal loop back mode and the SCI does not use the RxD pins. Single-wire SCI mode where the TxD pin is connected to the transmitter output.
4 M	 9-Bit or 8-Bit Mode Select 0 Normal — start + 8 data bits (LSB first) + stop. 1 Receiver and transmitter use 9-bit data characters start + 8 data bits (LSB first) + 9th data bit + stop.

CLKSB:CLKSA	TPM Clock Source to Prescaler Input
00	No clock selected (TPM counter disable)
01	Bus rate clock
10	Fixed system clock
11	External source

Table 16-4. TPM-Clock-Source Selection

Table 16-5	. Prescale	Factor	Selection
------------	------------	--------	-----------

PS2:PS1:PS0	TPM Clock Source Divided-by
000	1
001	2
010	4
011	8
100	16
101	32
110	64
111	128

16.3.2 TPM-Counter Registers (TPMxCNTH:TPMxCNTL)

The two read-only TPM counter registers contain the high and low bytes of the value in the TPM counter. Reading either byte (TPMxCNTH or TPMxCNTL) latches the contents of both bytes into a buffer where they remain latched until the other half is read. This allows coherent 16-bit reads in either big-endian or little-endian order which makes this more friendly to various compiler implementations. The coherency mechanism is automatically restarted by an MCU reset or any write to the timer status/control register (TPMxSC).

Reset clears the TPM counter registers. Writing any value to TPMxCNTH or TPMxCNTL also clears the TPM counter (TPMxCNTH:TPMxCNTL) and resets the coherency mechanism, regardless of the data involved in the write.







All TPM interrupts are listed in Table 16-9 which shows the interrupt name, the name of any local enable that can block the interrupt request from leaving the TPM and getting recognized by the separate interrupt processing logic.

Interrupt	Local Enable	Source	Description
TOF	TOIE	Counter overflow	Set each time the timer counter reaches its terminal count (at transition to next count value which is usually 0x0000)
CHnF	CHnIE	Channel event	An input capture or output compare event took place on channel n

Table 16-9	. Interrupt	Summary
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The TPM module will provide a high-true interrupt signal. Vectors and priorities are determined at chip integration time in the interrupt module so refer to the user's guide for the interrupt module or to the chip's complete documentation for details.

16.6.2 Description of Interrupt Operation

For each interrupt source in the TPM, a flag bit is set upon recognition of the interrupt condition such as timer overflow, channel-input capture, or output-compare events. This flag may be read (polled) by software to determine that the action has occurred, or an associated enable bit (TOIE or CHnIE) can be set to enable hardware interrupt generation. While the interrupt enable bit is set, a static interrupt will generate whenever the associated interrupt flag equals one. The user's software must perform a sequence of steps to clear the interrupt flag before returning from the interrupt-service routine.

TPM interrupt flags are cleared by a two-step process including a read of the flag bit while it is set (1) followed by a write of zero (0) to the bit. If a new event is detected between these two steps, the sequence is reset and the interrupt flag remains set after the second step to avoid the possibility of missing the new event.

16.6.2.1 Timer Overflow Interrupt (TOF) Description

The meaning and details of operation for TOF interrupts varies slightly depending upon the mode of operation of the TPM system (general purpose timing functions versus center-aligned PWM operation). The flag is cleared by the two step sequence described above.

16.6.2.1.1 Normal Case

Normally TOF is set when the timer counter changes from 0xFFFF to 0x0000. When the TPM is not configured for center-aligned PWM (CPWMS=0), TOF gets set when the timer counter changes from the terminal count (the value in the modulo register) to 0x0000. This case corresponds to the normal meaning of counter overflow.



Figure 17-2 shows an external host transmitting a logic 1 or 0 to the BKGD pin of a target HCS08 MCU. The host is asynchronous to the target so there is a 0-to-1 cycle delay from the host-generated falling edge to where the target perceives the beginning of the bit time. Ten target BDC clock cycles later, the target senses the bit level on the BKGD pin. Typically, the host actively drives the pseudo-open-drain BKGD pin during host-to-target transmissions to speed up rising edges. Because the target does not drive the BKGD pin during the host-to-target transmission period, there is no need to treat the line as an open-drain signal during this period.



Figure 17-2. BDC Host-to-Target Serial Bit Timing



Appendix A Electrical Characteristics

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for instance, either V_{SS} or V_{DD}) or the programmable pull-up resistor associated with the pin is enabled.

					Temp Rated	
#	Rating	Symbol	Value	Unit	Standard	AEC Grade 0
1	Supply voltage	V _{DD}	-0.3 to +5.8	V	•	•
2	Maximum current into V _{DD}	I _{DD}	120	mA	•	•
3	Digital input voltage	V _{In}	-0.3 to V _{DD} + 0.3	V	•	•
4	Instantaneous maximum current Single pin limit (applies to all port pins) ^{1, 2, 3}	Ι _D	± 25	mA	•	•
5	Storage temperature range	T _{stg}	-55 to 150	°C	•	•

Table	A-2.	Absolute	Maximum	Ratings
10010		/	in a / in a / in a	

¹ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive (V_{DD}) and negative (V_{SS}) clamp voltages, then use the larger of the two resistance values.

² All functional non-supply pins except $\overline{\text{RESET}}$ are internally clamped to V_{SS} and V_{DD}.

³ Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{In} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Ensure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if the clock rate is very low (which would reduce overall power consumption).



#	с		Symbol	Condition	Min	Typ ¹	Max	Unit	Temp Rated	
		Characteristic							Standard	AEC Grade 0
¹⁸ P		Low-voltage detection threshold		_						
	Ρ	low range V _{DD} falling V _{DD} rising	V _{LVD0}		2.48 2.54	2.56 2.62	2.64 2.70	v	•	•
¹⁹ P		Low-voltage warning threshold — high range 1 V _{DD} falling V _{DD} rising	V _{LVW3}		4.5 4.6	4.6 4.7	4.7 4.8	V	•	
	Ρ				4.48 4.58	4.6 4.7	4.72 4.82	V	_	•
²⁰ F	6	Low-voltage warning threshold — high range 0 V _{DD} falling V _{DD} rising	V _{LVW2}	_	4.2 4.3	4.3 4.4	4.4 4.5	V	•	_
	Ч				4.18 4.28	4.3 4.4	4.42 4.52	V	_	•
21	Ρ	Low-voltage warning threshold low range 1 V _{DD} falling V _{DD} rising	V _{LVW1}	_	2.84 2.90	2.92 2.98	3.00 3.06	v	•	٠
22	Ρ	Low-voltage warning threshold — low range 0 V _{DD} falling V _{DD} rising	V _{LVW0}	_	2.66 2.72	2.74 2.80	2.82 2.88	v	•	٠
23	т	Low-voltage inhibit reset/recover hysteresis	V _{hys}	5 V	_	100		mV	•	•
				3 V	—	60		mV	•	•
24	Ρ	Bandgap Voltage Reference ¹⁰	V _{BG}	_	1.18 1.17	1.202 1.202	1.21 1.22	V V	◆—	

Table A-6. DC Characteristics (continued)

 $^1\,$ Typical values are measured at 25°C. Characterized, not tested

² When IRQ or a pin interrupt is configured to detect rising edges, pulldown resistors are used in place of pullup resistors.

³ The specified resistor value is the actual value internal to the device. The pullup value may measure higher when measured externally on the pin.



Appendix A Electrical Characteristics

A.8 External Oscillator (XOSC) Characteristics

Table A-8. Oscillator Electrical Specifications (Temperature Range = -40 to 125°C Ambient)

		Rating	Symbol	Min	Typ ¹	Max	Unit	Temp Rated	
#	с							Standard	AEC Grade 0
		Oscillator crystal or resonator (EREFS = 1, ERCLKEN = 1)							
		Low range (RANGE = 0)	f _{lo}	32	—	38.4	kHz	•	•
1	С	High range (RANGE = 1) FEE or FBE mode ²	f _{hi}	1	—	5	MHz	•	•
		High range (RANGE = 1, HGO = 1) FBELP mode	f _{hi-hgo}	1	—	16	MHz	•	•
		High range (RANGE = 1, HGO = 0) FBELP mode		1	_	8	MHz	•	٠
2	—	Load capacitors	C _{1,} C ₂	See manufa	e crystal c cturer's re	or resonato	or ation.		
		Feedback resistor	R _F						
3	_	Low range (32 kHz to 100 kHz)		_	10	_	MΩ	•	•
		High range (1 MHz to 16 MHz)		_	1	_	MΩ	•	•
		Series resistor							
		Low range, low gain (RANGE = 0, HGO = 0)		_	0	_	kΩ	•	•
		Low range, high gain (RANGE = 0, HGO = 1)		_	100	_	kΩ	•	•
		High range, low gain (RANGE = 1, HGO = 0)		_	0	_	kΩ	•	•
4	-	High range, high gain (RANGE = 1, HGO = 1)	κ _S						
		≥ 8 MHz		_	0	0	kΩ	•	•
		4 MHz		_	0	10	kΩ	•	•
		1 MHz		_	0	20	kΩ	•	•
		Crystal start-up time ³							
		Low range, low gain (RANGE = 0, HGO = 0)	t CSTL-LP	_	200	_	ms	•	•
5	т	Low range, high gain (RANGE = 0, HGO = 1)	t CSTL-HGO	_	400	_	ms	٠	٠
		High range, low gain (RANGE = 1, HGO = 0) ⁴	t CSTH-LP	_	5	_	ms	•	•
		High range, high gain (RANGE = 1, HGO = 1) ⁴	^t CSTH-HGO	_	20	_	ms	•	•
6 Т		Square wave input clock frequency (EREFS = 0, ERCLKEN = 1)							
	₋	FEE or FBE mode ²		0.03125	_	5	MHz	•	•
		FBELP mode	f _{extal}	0	_	40	MHz	•	<u> </u>
		FBELP mode		0	—	36	MHz	—	•